# Low-Temperature Electronic Conductivity in Cu-doped CeO<sub>2</sub> Nanoparticles

## Motivation

Cerium oxide, or ceria, (CeO<sub>2</sub>) is a ceramic material with noteworthy electronic properties. Doping this material with copper has shown to be useful in the catalysis of several reactions, including the hightemperature reverse water gas shift reaction, and as a component in solid oxide fuel cells. In this project, we synthesize nanoparticles of copper-doped ceria (Cu-CeO<sub>2</sub>) and measure their conductivity using electrochemical impedance spectroscopy (EIS).

Background

Two mechanisms of electronic conduction have been hypothesized to occur in cerium oxide. At high temperatures, positively-charged oxygen vacancies formed by aliovalent doping or intrinsic Schottky defects can diffuse through the solid. At low temperatures, small polarons (distortions in the lattice caused by an extra electron in the 4f orbital) are mobile due to activation by optical phonons. At the temperatures measured in this experiment, the latter is most likely responsible for the conductivity observed.



Fig. 1. Small polaron hopping in  $CeO_2$ . (DFT calculations predict that the reduced Ce-O bond length is 0.091 Å longer than the bond length in a perfect crystal) [2].



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Fig. 3. Nyquist plots for (a), 2% Cu doping, (b), 4% Cu doping, (c), 8% Cu doping. (d) is a magnified version of (c). The AC potential used was 10 mV, and the frequency was swept between 1 MHz and 1Hz.

Table 1. EIS results for each doping concentration at each temperature measured. (When the lattice resistance and grain boundary resistance were similar in magnitude, the model was changed to a single parallel resistor-CPE).

T (°C)	$R_{g}\left(M\Omega ight)$	$Q_{0_g}\left(S{ullet}s^n ight)$	$n_g$	$R_{gb}\left(M\Omega ight)$	$Q_{0_{gb}}\left(S{ullet}s^n ight)$	$n_{gb}$
100°C	3.0712	$2.2279 \cdot 10^{-11}$	1.121	0.26337	$1.7067 \cdot 10^{-10}$	0.92284
150°C	1.9824	$2.469 \cdot 10^{-12}$	1.062	N/A	N/A	N/A
200°C	1.7551	$3.540 \cdot 10^{-12}$	1.033	N/A	N/A	N/A
Nanoparticulate 2% Cu-CeO <sub>2</sub> EIS results for various temperatures						

Ĭ	T (°C)	$R_{g}\left(M\Omega ight)$	$Q_{0_{g}}\left(S{ullet}s^{n} ight)$	$n_g$	$R_{gb}\left(M\Omega ight)$	$Q_{0_{gb}}\left(S{ullet}s^n ight)$	$n_{gb}$
	100°C	7.7422	$2.753 \cdot 10^{-10}$	0.84652	0.026272	$2.558 \cdot 10^{-13}$	1.264
	150°C	1.017	$1.879 \cdot 10^{-10}$	0.9396	0.142200	$1.807 \cdot 10^{-10}$	0.94181
	200°C	0.389860	$8.648 \cdot 10^{-10}$	0.77437	0.000995	$8.092 \cdot 10^{-11}$	1.411

Nanoparticulate 4% Cu-CeO<sub>2</sub> EIS results for various temperature



Moment-Based	
Average value:	0.813 <i>µ</i> m
RMS roughness (Sq):	108.4 nm
RMS (grain-wise):	108.4 nm
Mean roughness (Sa):	81.1 nm
Skew (Ssk):	-0.3319
Excess kurtosis:	1.473
Order-Based	
Minimum:	0.000 µm
Maximum:	1.536 µm
Median:	0.819 µm
Maximum peak height (Sp	o): 0.723 μm
Maximum pit depth (Sv):	0.813 µm
Maximum height (Sz):	1.536 µm
Hybrid	
Projected area:	225.0 µm²
Surface area:	256.4 µm <sup>2</sup>
Volume:	$183.0 \mu m^3$
Surface slope (Sdg):	0.6158
Variation:	$103.2 \mu m^2$
Inclination 0:	0.40 deg
Inclination d:	48.89 deg
nonnauon y.	10.00 deg
Other	
Scan line discrepancy:	10.51 × 10 <sup>-3</sup>

Fig. 4. Sample AFM micrograph of heat-treated pellet surface

### Table 2. Relevant pellet dimensions

Composition	Electrode $\mathrm{SA_{top}}(mm)^2$	Electrode $SA_{bottom}  (mm)^2$	$\mathbf{SA}_{\mathbf{adjusted}} \ (mm)^2$	Pellet Thickness(mm)
2% Cu-CeO <sub>2</sub>	100	106	115	0.30
4% Cu-CeO <sub>2</sub>	95	102	110	0.30
8% Cu-CeO <sub>2</sub>	98	103	113	0.30

 $R_{gb}\left(M\Omega
ight) ~\left|~ Q_{0_{qb}}\left(S{ullet}s^n
ight)~
ight|~ n_{gb}$  $3.368 \cdot 10^{-13}$ 1.055 $2.714 \cdot 10^{-12}$  | 1.019 | 2.008 \cdot 10^5  $0^{\circ}$ C | 0.207500 |  $6.6360 \cdot 10^{-10}$  | 0.8757 | 0.074913 |  $9.825 \cdot 10^{-11}$  | 0.96738

noparticulate 8% Cu-CeO<sub>2</sub> EIS results for various temperatures



Table 3. Pre-exponential factor, activation energy, and the mobility, jump rate, and charge carrier density at 200 Celsius for different doping concentrations

Cu (at. %)	$\sigma_0\left(K/(\Omega^{ullet}m) ight)$	$E_{a}\left( eV ight)$	$\mu \left(200^\circ C ight) \left(cm^2/V{ullet s} ight)$	$\Gamma\left(200^\circ C ight)(s^{-1})$	$n\left(200\degree C ight)\left(m^{-3} ight)$
2%	1.34	0.05	$6.4 \cdot 10^{-2}$	$8.87 \cdot 10^{11}$	$1.90 \cdot 10^{22}$
4%	138	0.21	$1.3 \cdot 10^{-3}$	$1.75 \cdot 10^{10}$	$4.16 \cdot 10^{24}$
8%	4376	0.34	$5.2 \cdot 10^{-5}$	$7.22 \cdot 10^8$	$1.96 \cdot 10^{26}$

Future work could involve broadening the range of dopants tested and testing at finer temperature increments. More care could also be taken to shield the impedance bridge, in our case a Solartron 1260A, from vibrations and electromagnetic interference by making use of a Faraday cage, for instance. Polishing the sample surface may also lead to less noise in the low-frequency range of the Nyquist plots.

## Synthesis & Preparation

Nanoparticles were synthesized in a 1310-minute co-precipitation reaction. Particles were centrifuged, dried and powderized. Samples were pressed into pellets without binder using 5000 psi of uniaxial pressure for 10 minutes and heat treated up to a maximum temperature of 350°C for 8 hours. Prior PDF analysis done by Haolan Sun showed the particle size ranged from 50 Å to 30 Å depending on the Cu concentration.

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[1] H.L. Tuller, A.S. Nowick, Journal of Physics and Chemistry of Solids, Volume 38, Issue 8 (1977) Pages 859-867 [2] José J. Plata, Antonio M. Márquez, and Javier Fdez. Sanz, The Journal of Physical Chemistry C (2013) 117(28)